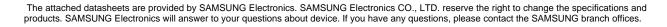
# **Document Title**

# 512Kx8 bit Low Power and Low Voltage CMOS Static RAM

# **Revision History**

Revision No.	History	<u>Draft Data</u>	<u>Remark</u>
0.0	Initial Draft	January 13, 1998	Advance
0.1	Revisied - Speed bin change KM68U4000C: 85/100ns $\rightarrow$ 70/85/100ns - DC Characteristics change lcc: 5mA at read/write $\rightarrow$ 4mA at read lcc1: 3mA $\rightarrow$ 4mA lcc2: 35mA $\rightarrow$ 30mA lsB: 0.5mA $\rightarrow$ 0.3mA lsB1: 10 $\mu$ A $\rightarrow$ 15 $\mu$ A for commercial parts - Add 32-TSOP1-0820	June 12, 1998	Preliminary
0.11	Errata correct - 32-TSOP1-0813 products: T → TG	November 7, 1998	
1.0	Finalize	January 15, 1999	Final





# 512K×8 bit Low Power and Low Voltage CMOS Static RAM

### **FEATURES**

Process Technology: TFTOrganization: 512K×8

Power Supply Voltage

K6T4008V1C Family: 3.0~3.6V K6T4008U1C Family: 2.7~3.3V

- Low Data Retention Voltage: 2V(Min)
- Three state output and TTL Compatible
- Package Type: 32-SOP-525, 32-TSOP2-400F/R 32-TSOP1-0820F, 32-TSOP1-0813.4F

### **GENERAL DESCRIPTION**

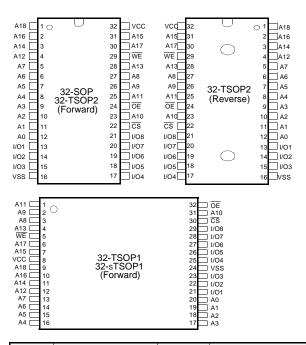
The K6T4008V1C and K6T4008U1C families are fabricated by SAMSUNG's advanced CMOS process technology. The families support various operating temperature range and have various package type for user flexibility of system design. The families also support low data retention voltage for battery back-up operation with low data retention current.

### PRODUCT FAMILY

				Power Dis		
Product Family	Operating Temperature	Vcc Range	Speed	Standby (Isв1, Max)	Operating (Icc2, Max)	PKG Type
K6T4008V1C-B	Commercial(0~70°C)	3.0~3.6V	70 <sup>1)</sup> /85ns	15uA		32-SOP
K6T4008U1C-B	Commercial(0°70°0)	2.7~3.3V	70 <sup>1)</sup> /85/100ns	ΙσμΑ	30mA	32-TSOP2-F/R
K6T4008V1C-F	Industrial(-40~85°C)	3.0~3.6V	70 <sup>1)</sup> /85ns	20uA	John	32-TSOP1-F 32-sTSOP1-F
K6T4008U1C-F	111003t1lai(-40~05 O)	2.7~3.3V	70 <sup>1)</sup> /85/100ns	20μΛ		32-3130F1-F

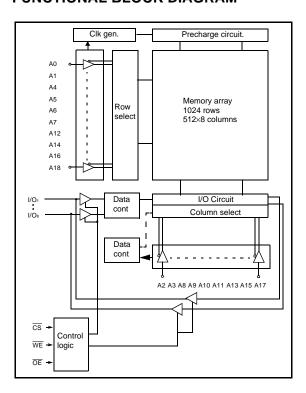
<sup>1.</sup> The parameter is measured with 30pF test load.

### PIN DESCRIPTION



Name	Function	Name	Function
A0~A18	Address Inputs	Vcc	Power
WE	Write Enable Input	Vss	Ground
CS	Chip Select Input	I/O1~I/O8	Data Inputs/Outputs
ŌE	Output Enable Input		

### **FUNCTIONAL BLOCK DIAGRAM**



SAMSUNG ELECTRONICS CO., LTD. reserves the right to change products and specifications without notice.



### **PRODUCT LIST**

Commercial 1	Temp Products(0~70°C)	Industrial Ten	np Products(-40~85°C)
Part Name	Function	Part Name	Function
K6T4008V1C-GB70	32-SOP, 70ns, 3.3V, LL	K6T4008V1C-GF70	32-SOP, 70ns, 3.3V, LL
K6T4008V1C-GB85	32-SOP, 85ns, 3.3V, LL	K6T4008V1C-GF85	32-SOP, 85ns, 3.3V, LL
K6T4008V1C-VB70	32-TSOP2-F, 70ns, 3.3V, LL	K6T4008V1C-VF70	32-TSOP2-F, 70ns, 3.3V, LL
K6T4008V1C-VB85	32-TSOP2-F, 85ns, 3.3V, LL	K6T4008V1C-VF85	32-TSOP2-F, 85ns, 3.3V, LL
K6T4008V1C-MB70	32-TSOP2-R, 70ns, 3.3V, LL	K6T4008V1C-MF70	32-TSOP2-R, 70ns, 3.3V, LL
K6T4008V1C-MB85	32-TSOP2-R, 85ns, 3.3V, LL	K6T4008V1C-MF85	32-TSOP2-R, 85ns, 3.3V, LL
K6T4008V1C-TB70	32-TSOP1-F, 70ns, 3.3V, LL	K6T4008V1C-TF70	32-TSOP1-F, 70ns, 3.3V, LL
K6T4008V1C-TB85	32-TSOP1-F, 85ns, 3.3V, LL	K6T4008V1C-TF85	32-TSOP1-F, 85ns, 3.3V, LL
K6T4008V1C-YB70	32-sTSOP1-F, 70ns, 3.3V, LL	K6T4008V1C-YF70	32-sTSOP1-F, 70ns, 3.3V, LL
K6T4008V1C-YB85	32-sTSOP1-F, 85ns, 3.3V, LL	K6T4008V1C-YF85	32-sTSOP1-F, 85ns, 3.3V, LL
K6T4008U1C-GB70	32-SOP, 70ns, 3.0V, LL	K6T4008U1C-GF70	32-SOP, 70ns, 3.0V, LL
K6T4008U1C-GB85	32-SOP, 85ns, 3.0V, LL	K6T4008U1C-GF85	32-SOP, 85ns, 3.0V, LL
K6T4008U1C-GB10	32-SOP, 100ns, 3.0V, LL	K6T4008U1C-GF10	32-SOP, 100ns, 3.0V, LL
K6T4008U1C-VB70	32-TSOP2-F, 70ns, 3.0V, LL	K6T4008U1C-VF70	32-TSOP2-F, 70ns, 3.0V, LL
K6T4008U1C-VB85	32-TSOP2-F, 85ns, 3.0V, LL	K6T4008U1C-VF85	32-TSOP2-F, 85ns, 3.0V, LL
K6T4008U1C-VB10	32-TSOP2-F, 100ns, 3.0V, LL	K6T4008U1C-VF10	32-TSOP2-F, 100ns, 3.0V, LL
K6T4008U1C-MB70	32-TSOP2-R, 70ns, 3.0V, LL	K6T4008U1C-MF70	32-TSOP2-R, 70ns, 3.0V, LL
K6T4008U1C-MB85	32-TSOP2-R, 85ns, 3.0V, LL	K6T4008U1C-MF85	32-TSOP2-R, 85ns, 3.0V, LL
K6T4008U1C-MB10	32-TSOP2-R, 100ns, 3.0V, LL	K6T4008U1C-MF10	32-TSOP2-R, 100ns, 3.0V, LL
K6T4008U1C-TB70	32-TSOP1-F, 70ns, 3.0V, LL	K6T4008U1C-TF70	32-TSOP1-F, 70ns, 3.0V, LL
K6T4008U1C-TB85	32-TSOP1-F, 85ns, 3.0V, LL	K6T4008U1C-TF85	32-TSOP1-F, 85ns, 3.0V, LL
K6T4008U1C-TB10	32-TSOP1-F, 100ns, 3.0V, LL	K6T4008U1C-TF10	32-TSOP1-F, 100ns, 3.0V, LL
K6T4008U1C-YB70	32-sTSOP1-F, 70ns, 3.0V, LL	K6T4008U1C-YF70	32-sTSOP1-F, 70ns, 3.0V, LL
K6T4008U1C-YB85	32-sTSOP1-F, 85ns, 3.0V, LL	K6T4008U1C-YF85	32-sTSOP1-F, 85ns, 3.0V, LL
K6T4008U1C-YB10	32-sTSOP1-F, 100ns, 3.0V, LL	K6T4008U1C-YF10	32-sTSOP1-F, 100ns, 3.0V, LL

### **FUNCTIONAL DESCRIPTION**

CS	OE	WE	I/O	Mode	Power
Н	X <sup>1)</sup>	X <sup>1)</sup>	High-Z	Deselected	Standby
L	Н	Н	High-Z	Output Disabled	Active
L	L	Н	Dout	Read	Active
L	X <sup>1)</sup>	L	Din	Write	Active

<sup>1.</sup> X means don't care (Must be in low or high state)

### **ABSOLUTE MAXIMUM RATINGS**(1)

Item	Symbol	Ratings	Unit	Remark
Voltage on any pin relative to Vss	VIN, VOUT	-0.5 to Vcc+0.5	V	-
Voltage on Vcc supply relative to Vss	Vcc	-0.3 to 4.6	V	-
Power Dissipation	PD	1.0	W	-
Storage temperature	Тѕтс	-65 to 150	°C	-
Operating Temperature	TA	0 to 70	°C	K6T4008V1C-L, K6T4008U1C-L
Sporating remperature		-40 to 85	°C	K6T4008V1C-P, K6T4008U1C-P

Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Functional operation should be restricted to recommended operating condition. Exposure to absolute maximum rating conditions for extended periods may affect reliability.



### **RECOMMENDED DC OPERATING CONDITIONS**(1)

Item	Symbol	Product	Min	Тур	Max	Unit
Supply voltage	Vcc	K6T4008V1C Family	3.0	3.3	3.6	V
		K6T4008U1C Family	2.7	3.0	3.3	·
Ground	Vss	All Family	0	0	0	V
Input high voltage	ViH	K6T4008V1C, K6T4008U1C Family	2.2	-	Vcc+0.3 <sup>2)</sup>	V
Input low voltage	VIL	K6T4008V1C, K6T4008U1C Family	-0.3 <sup>3)</sup>	-	0.6	V

#### Note:

- Commercial Product : Ta=0 to 70°C, otherwise specified Industrial Product : Ta=-40 to 85°C, otherwise specified
- 2. Overshoot: Vcc+2.0V in case of pulse width ≤ 30ns
- 3. Undershoot: -2.0V in case of pulse width ≤ 30ns
- 4. Overshoot and undershoot are sampled, not 100% tested.

## CAPACITANCE1) (f=1MHz, TA=25°C)

Item	Symbol	Test Condition	Min	Max	Unit
Input capacitance	CIN	VIN=0V	-	8	pF
Input/Output capacitance	Сю	Vio=0V	-	10	pF

<sup>1.</sup> Capacitance is sampled, not 100% tested

### DC AND OPERATING CHARACTERISTICS

Item	Symbol	Test Conditions	Min	Тур	Max	Unit
Input leakage current	ILI	V <sub>IN</sub> =Vss to Vcc	-1	-	1	μΑ
Output leakage current	ILO	CS=VIH or OE=VIH or WE=VIL VIO=Vss to Vcc	-1	-	1	μΑ
Operating power supply current	Icc	IIO=0mA, CS=VIL, VIN=VIL or VIH, Read	-	-	4	mA
Average operating current	Icc1	Cycle time=1µs, 100% duty, I₁o=0mA CS≤0.2V,VıN≤0.2V or VıN≥Vcc-0.2V	-	-	4	mA
Average operating outlent	ICC2	Cycle time=Min, 100% duty, Iio=0mA, CS=VIL, VIN=VIH or VIL	-	-	30	mA
Output low voltage	Vol	IoL=2.1mA	-	-	0.4	V
Output high voltage	Voн	IOH=-1.0mA	2.2	-	-	V
Standby Current(TTL)	IsB	CS=VIH, Other inputs = VIL or VIH	-	-	0.3	mA
Standby Current (CMOS)	ISB1	CS≥Vcc-0.2V, Other inputs=0~Vcc	-	-	15 <sup>1)</sup>	μΑ

<sup>1.</sup> Industrial product = 20μA

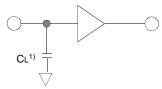


### **AC OPERATING CONDITIONS**

TEST CONDITIONS(Test Load and Input/Output Reference)

Input pulse level: 0.4 to 2.2V
Input rising and falling time: 5ns
Input and output reference voltage:1.5V
Output load(see right): CL=100pF+1TTL
CL¹)=30pF+1TTL

1. 70ns product



1. Including scope and jig capacitance

# AC CHARACTERISTICS (K6T4008V1C Family: Vcc=3.0~3.6V, K6T4008U1C Family: Vcc=2.7~3.3V Commercial product:: Ta=0 to 70°C, Industrial product: Ta=-40 to 85°C)

			Speed Bins						
Parameter List		Symbol	70ns		85	ins	100ns		Units
			Min	Max	Min	Max	Min	Max	
	Read cycle time	trc	70	-	85	-	100	-	ns
	Address access time	tAA	-	70	-	85	-	100	ns
	Chip select to output	tco	-	70	-	85	-	100	ns
	Output enable to valid output	toE	-	35	-	40	-	50	ns
Read	Chip select to low-Z output	tLZ	10	-	10	-	10	-	ns
	Output enable to low-Z output	toLZ	5	-	5	-	5	-	ns
	Chip disable to high-Z output	tHZ	0	25	0	25	0	30	ns
	Output disable to high-Z output	tonz	0	25	0	25	0	30	ns
	Output hold from address change	tон	10	-	10	-	15	-	ns
	Write cycle time	twc	70	-	85	-	100	-	ns
	Chip select to end of write	tcw	60	-	70	-	80	-	ns
	Address set-up time	tas	0	-	0	-	0	-	ns
	Address valid to end of write	taw	60	-	70	-	80	-	ns
Write	Write pulse width	twp	55	-	55	-	70	-	ns
vviile	Write recovery time	twr	0	-	0	-	0	-	ns
	Write to output high-Z	twnz	0	25	0	25	0	30	ns
	Data to write time overlap	tow	30	-	35	-	40	-	ns
	Data hold from write time	tDH	0	-	0	-	0	-	ns
	End write to output low-Z	tow	5	-	5	-	5	-	ns

### **DATA RETENTION CHARACTERISTICS**

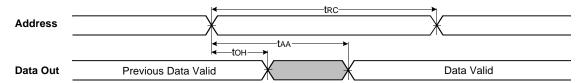
Item Symbol		Test Condition	Min	Тур	Max	Unit
Vcc for data retention	VDR	CS≥Vcc-0.2V	2.0	-	3.6	V
Data retention current	Idr	Vcc=3.0V, CS≥Vcc-0.2V	-	0.5	15 <sup>1)</sup>	μΑ
Data retention set-up time	tsdr	See data retention waveform	0	-	-	ms
Recovery time	trdr	- 500 data rotomion waveform	5	-	-	1113

<sup>1.</sup> Industrial product = 20μA

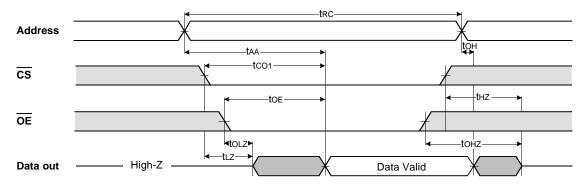


### **TIMMING DIAGRAMS**

TIMING WAVEFORM OF READ CYCLE(1) (Address Controlled, CS=OE=VIL, WE=VIH)



### TIMING WAVEFORM OF READ CYCLE(2) (WE=VIH)

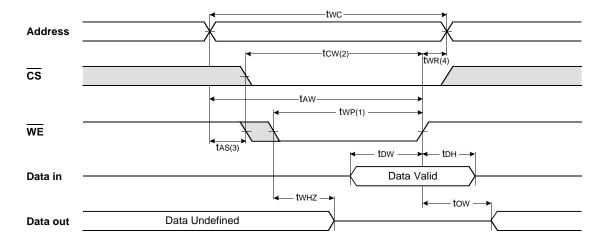


### NOTES (READ CYCLE)

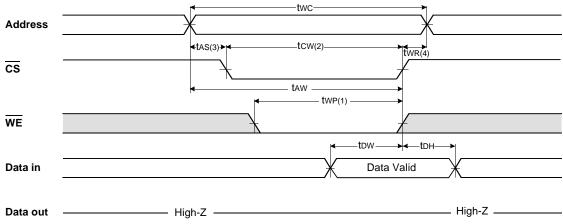
- 1. tHZ and tOHZ are defined as the time at which the outputs achieve the open circuit conditions and are not referenced to output voltage levels.
- 2. At any given temperature and voltage condition, tHZ(Max.) is less than tLZ(Min.) both for a given device and from device to device interconnection.



### TIMING WAVEFORM OF WRITE CYCLE(1) (WE Controlled)



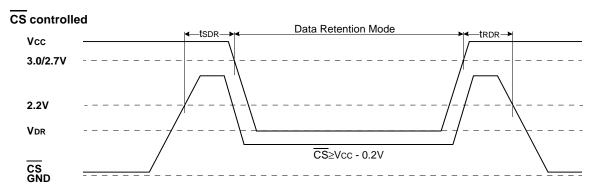
### TIMING WAVEFORM OF WRITE CYCLE(2) (CS Controlled)



### NOTES (WRITE CYCLE)

- 1. A write occurs during the overlap of a low  $\overline{\text{CS}}$  and a low  $\overline{\text{WE}}$ . A write begins at the latest transition among  $\overline{\text{CS}}$  going Low and  $\overline{\text{WE}}$  going low: A write end at the earliest transition among  $\overline{\text{CS}}$  going high and  $\overline{\text{WE}}$  going high,  $\overline{\text{twp}}$  is measured from the begining of write to the end of write.
- 2. tcw is measured from the  $\overline{\text{CS}}$  going low to end of write.
- 3. tAS is measured from the address valid to the beginning of write.
- 4. twn is measured from the end of write to the address change. twn applied in case a write ends as  $\overline{\text{CS}}$  or  $\overline{\text{WE}}$  going high.

## **DATA RETENTION WAVE FORM**

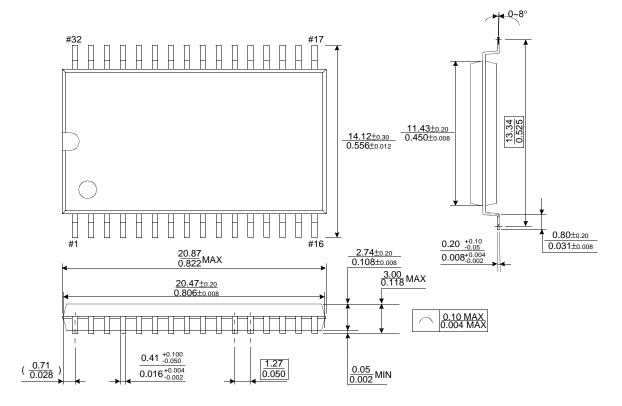




### **PACKAGE DIMENSIONS**

Units: millimeters(inches)

### 32 PIN PLASTIC SMALL OUTLINE PACKAGE (525mil)

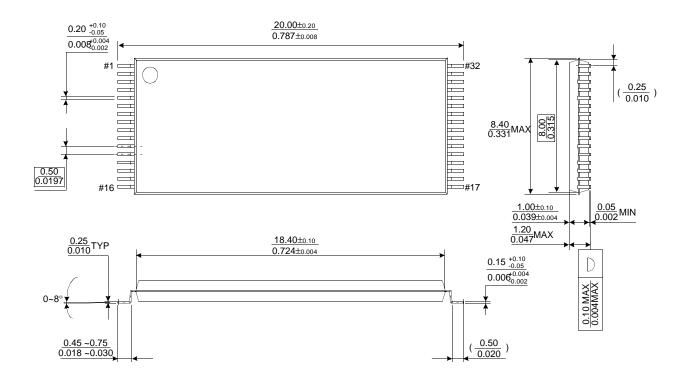




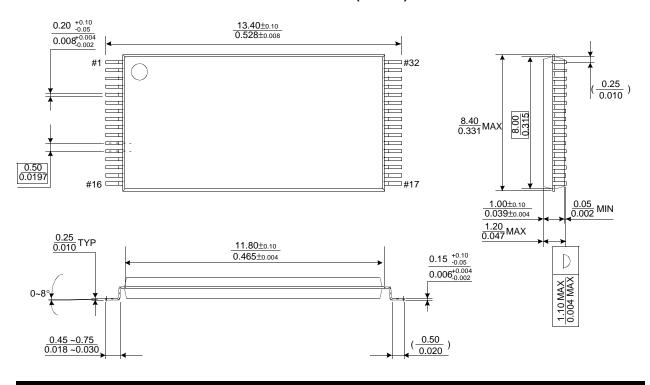
### **PACKAGE DIMENSIONS**

Units: millimeters(inches)

### 32 PIN THIN SMALL OUTLINE PACKAGE TYPE I (0820F)



### 32 PIN SMALLER THIN SMALL OUTLINE PACKAGE TYPE I (0813.4F)





### **PACKAGE DIMENSIONS**

Units: millimeters(inches)

